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Reliability over Consecutive Releases of a Semiconductor Optical Endpoint Detection Software System Developed in a Small Company

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HIGHLIGHTS

- Limited data available from a small company can be used for reliability analysis
- We used Laplace trend test to demonstrate an overall reliability growth trend
- We used IDRM to determine system stability and operational reliability
- Reliability growth was demonstrated using 3 SRGMs (GO, MO, S models)
- SRGMs fitted the observations well and provided accurate reliability predictions

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